Notice of References Cited Application/Control No. | Applicant(s)/Patent Under | Reexamination | LIN ET AL. | Examiner | Art Unit | Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2006/0000711	01-2006	Lin et al.	204/404
*	В	US-2005/0082174	04-2005	Kendig et al.	205/775.5
*	С	US-2006/0011475	01-2006	Lin et al.	204/404
*	D	US-5,378,991	01-1995	Anderson et al.	324/557
*	E	US-5,519,330	05-1996	Yamauchi et al.	324/700
*	F	US-6,026,691	02-2000	Laird et al.	73/808
*	G	US-6,446,881	09-2002	You, Jung	239/146
*	Н	US-5,700,127	12-1997	Harada et al.	414/416.08
*	Ι.	US-2005/0011537	01-2005	Toshima et al.	134/019
*	J	US-6,466,881	10-2002	Shih et al.	702/84
*	к	US-2001/0001441	05-2001	Zdunek et al.	205/791
*	L	US-5,535,618	07-1996	Konieczka, John	73/49.3
	м	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	α					
	R	·				
	s					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	C	
	٧	
	w	
	x	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.